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You, Y.; Hayes, J.P.;
Computer-Aided Design of Integrated Circuits and Systems, IEEE Transaction on , Volume: 7 , Issue: 12 , Dec. 1988
Pages:1261 - 1271

[Abstract]   [PDF Full-Text (840 KB)]   **IEEE JNL**

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2 **A new architecture of filter designed for testability**
Lutovac, M.D.; Rabrenovic, D.M.;
Microelectronics, 1995. Proceedings., 1995 20th International Conference on , Volume: 2 , 12-14 Sept. 1995
Pages:753 - 757 vol.2

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